



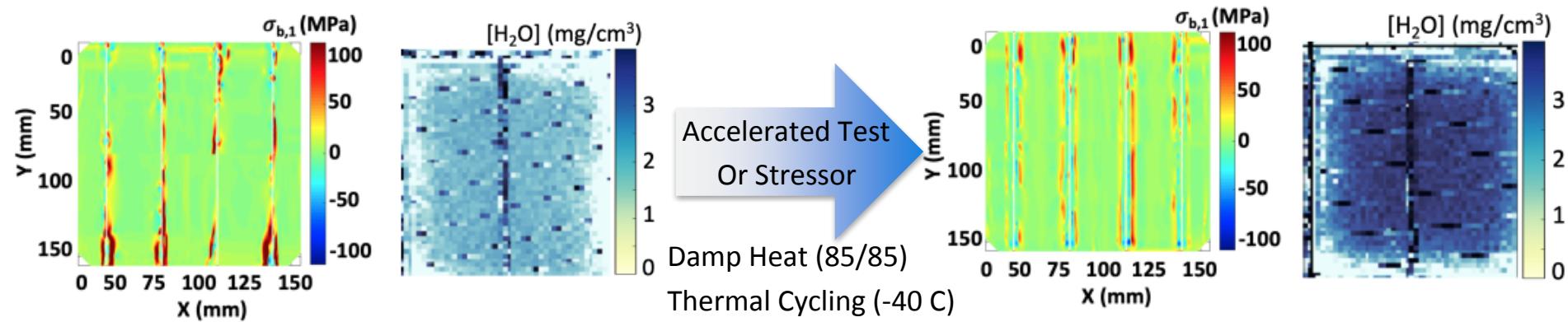
# In-situ Mapping of Deformation in Crystalline Silicon Modules: Understanding the Effects of Viscoelasticity

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# Motivation: In-situ Module Stress Analysis and Improved Modeling

- Stress in cells during module manufacture + operation → cell cracks, moisture ingress, power loss
- **Goal:** Identify how operating conditions affect cell → improve materials, processes to extend module reliability
- **Proposed Methods:** Quantify and correlate stresses in-situ by X-ray Topography (XRT), FEM modelling, and water content by Water Reflectometric Detection (WaRD)

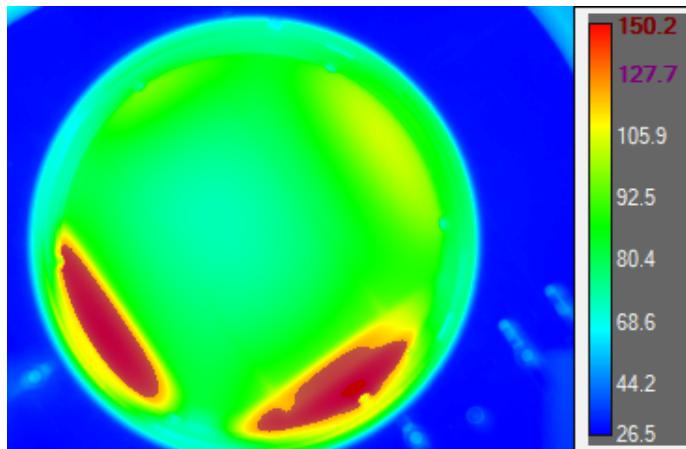
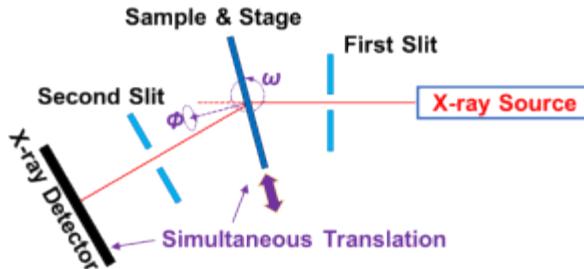


# Water Concentration Mapping with WaRD (UCSD Please add)

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- Measurement of water signature in infrared
- Example Water Mapping for half-cell, diffusion profile calculations, POE vs. EVA

# In-situ Deflection Measurement via X-Ray Topography (XRT)

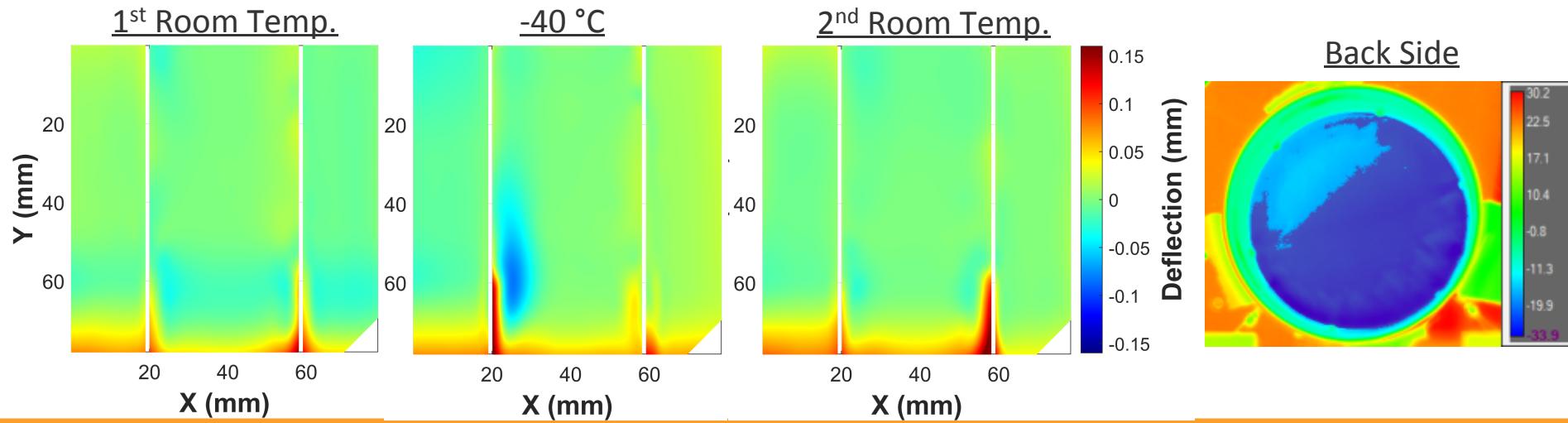


- Sample held 85C after drying in N<sub>2</sub> atmosphere
- Add representative XRT map

# In-situ Deflection Mapping at Low Temperature

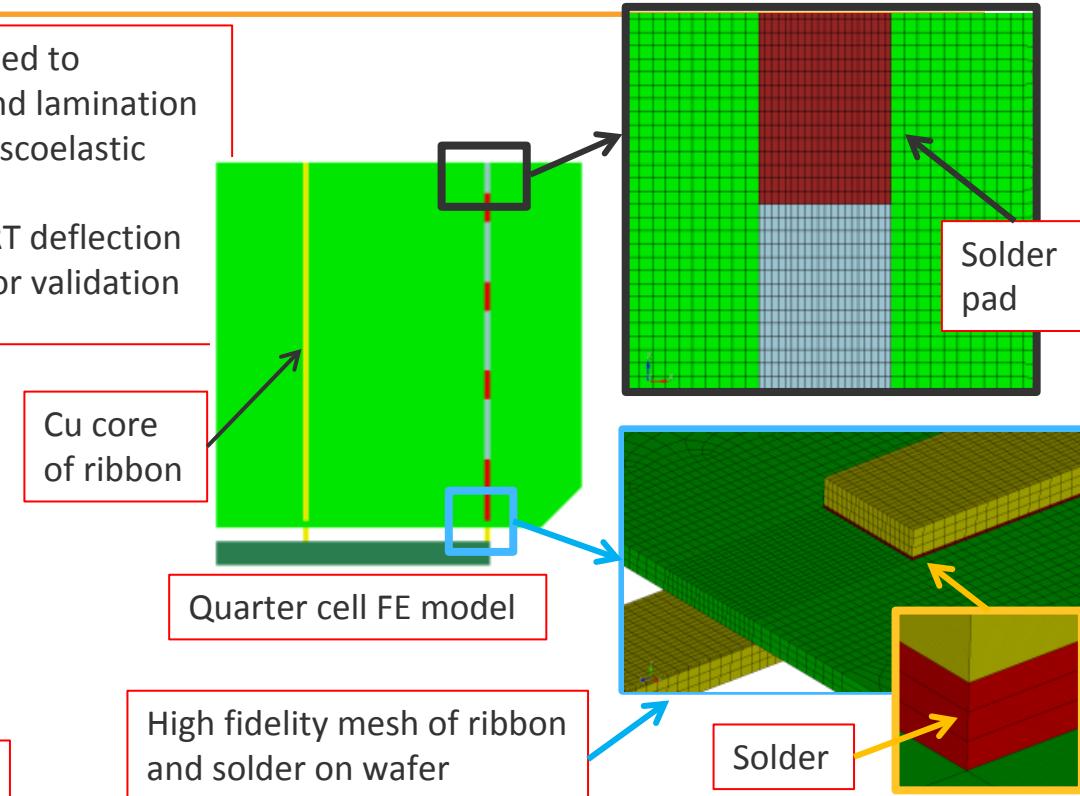
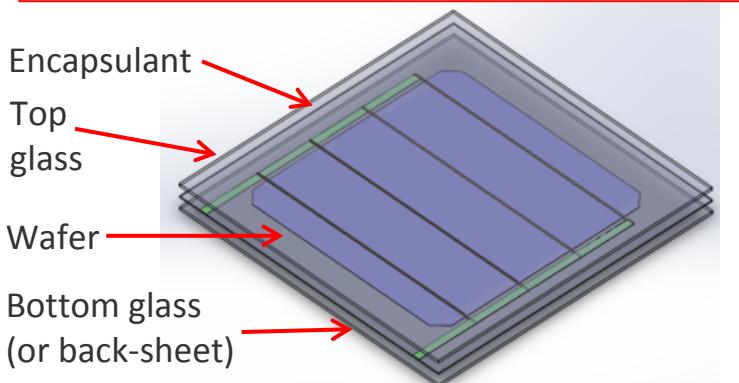
**Objective:** To map deflection below the glass transition temperature of the encapsulation materials

**Progress:** Measurements across a thermal cycle show deflection change between low and room temperatures



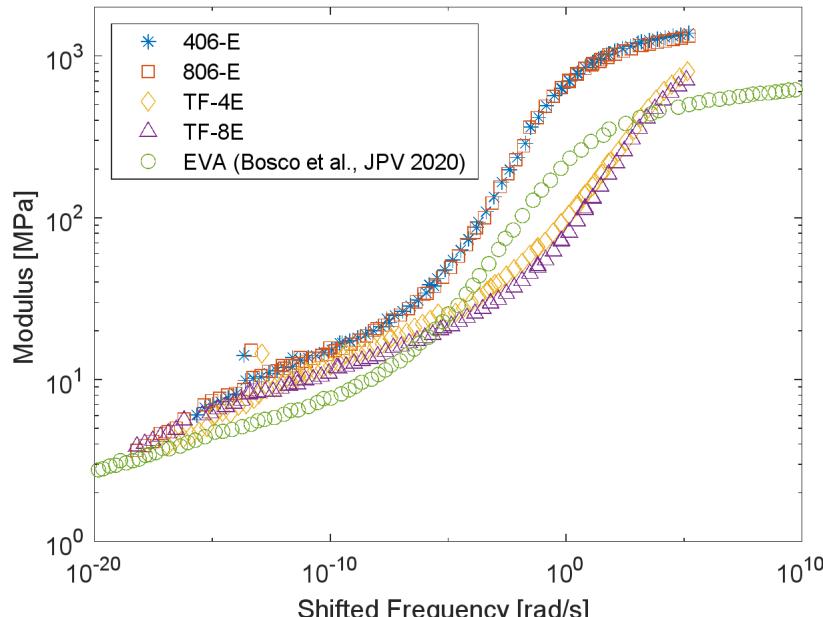
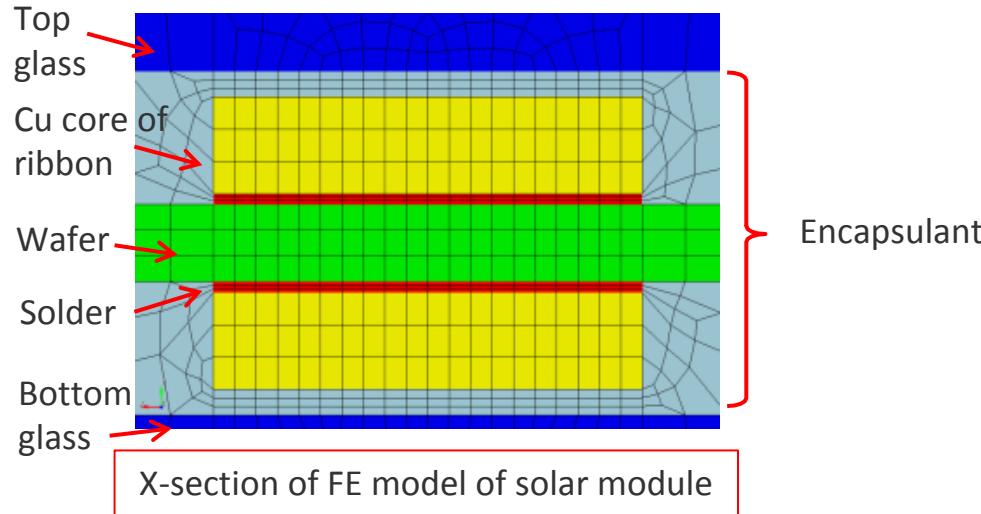
# FEA to Predict Manufacturing Process Induced Residual Stresses in Solar Cells

- Detailed FE model of solar module is developed to simulate residual stresses due to soldering and lamination processes including effect of encapsulant's viscoelastic property
- FE model results will be compared against XRT deflection maps determined with actual solar module for validation



# FEA to Predict Manufacturing Process Induced Residual Stresses in Solar Cells

- Measured mechanical properties for two EVA and two POE encapsulants
- Experimental master curves will be implemented in a higher fidelity material model for finite element simulations



Measured master curves for encapsulant materials used in minimodule samples

# Acknowledgements

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